

Notice of References Cited

Application/Control No.

10/542,171

Applicant(s)/Patent Under
Reexamination
TANAKA ET AL.

Examiner

Karie O'Neill Apicella

Art Unit

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0194589	10-2003	Pratt et al.	429/22
	B	US-			
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	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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